

Abstracts

The Evolution of Automated Microwave Measurements

J.H. Meyer. "The Evolution of Automated Microwave Measurements." 1975 MTT-S International Microwave Symposium Digest of Technical Papers 75.1 (1975 [MWSYM]): 92-94.

Microwave measurements lend themselves to automation because many readings and much computation is often needed to achieve reasonable accuracies. The expense of automated microwave measurements has limited their widespread use for general measurements.

However, an international standard for instrument interfaces, more off-the-shelf programmable instruments, and the advent of inexpensive calculator controllers will dramatically increase the utilization of automated microwave measurement techniques.

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